

<b>Notice of References Cited</b>	Application/Control No. 10/656,177	Applicant(s)/Patent Under Reexamination LUTSCH ET AL.	
	Examiner Son V Nguyen	Art Unit 2839	Page 1 of 1

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	C	US-6,102,726 A	08-2000	Tsuji et al.	439/352
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**NON-PATENT DOCUMENTS**

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